

Search Notes

Application/Control No.

10/762,670

Examiner

Alan S. Chen

Applicant(s)/Patent under
Reexamination

SCHLONSKI ET AL.

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	1/4/2007	ASC
limited text search; 710/15-19,62,72	1/4/2007	ASC